Features

- Fast Read Access Time 70 ns
- **Dual Voltage Range Operation**
 - Unregulated Battery Power Supply Range, 2.7V to 3.6V or Standard 5V \pm 10% Supply Range
- Pin Compatible with JEDEC Standard AT27C512R
- Low Power CMOS Operation
 - 20 μ A max. (less than 1 μ A typical) Standby for V_{CC} = 3.6V
 - 29 mW max. Active at 5 MHz for V_{CC} = 3.6V
- JEDEC Standard Surface Mount Packages
 - 32-Lead PLCC
 - 28-Lead 330-mil SOIC
 - 28-Lead TSOP
- High Reliability CMOS Technology
 - 2,000V ESD Protection
 - 200 mA Latchup Immunity
- Rapid[™] Programming Algorithm 100 µs/byte (typical)
- **CMOS** and TTL Compatible Inputs and Outputs
 - JEDEC Standard for LVTTL and LVBO
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

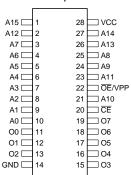
Description

The AT27BV512 is a high performance, low power, low voltage 524,288-bit one-time programmable read only memory (OTP EPROM) organized as 64K by 8 bits. It requires only one supply in the range of 2.7V to 3.6V in normal read mode operation, making it ideal for fast, portable systems using either regulated or unregulated battery power. (continued)

Pin Configurations

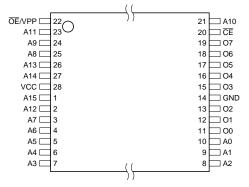
| Pin Name | Function |
|----------|----------------------------------|
| A0 - A15 | Addresses |
| O0 - O7 | Outputs |
| CE | Chip Enable |
| ŌE/VPP | Output Enable/ Program Supply |
| NC | No Connect |



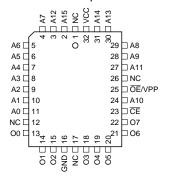


TSOP Top View





PLCC Top View



Note: PLCC package pins 1 and 17 are

DON'T CONNECT.





512K (64K x 8) Unregulated Battery-Voltage™ **High Speed OTP EPROM**

AT27BV512

Rev. 0602B-10/98



Atmel's innovative design techniques provide fast speeds that rival 5V parts while keeping the low power consumption of a 3V supply. At $V_{CC}=2.7V$, any byte can be accessed in less than 70 ns. With a typical power consumption of only 18 mW at 5 MHz and $V_{CC}=3V$, the AT27BV512 consumes less than one fifth the power of a standard 5V EPROM.

Standby mode supply current is typically less than 1 μ A at 3V. The AT27BV512 simplifies system design and stretches battery lifetime even further by eliminating the need for power supply regulation.

The AT27BV512 is available in industry standard JEDEC-approved one-time programmable (OTP) plastic PLCC, SOIC, and TSOP packages. All devices feature two-line control (CE, OE) to give designers the flexibility to prevent bus contention.

The AT27BV512 operating with V $_{CC}$ at 3.0V produces TTL level outputs that are compatible with standard TTL logic devices operating at V $_{CC}$ = 5.0V. At V $_{CC}$ = 2.7V, the part is compatible with JEDEC approved low voltage battery operation (LVBO) interface specifications. The device is also capable of standard 5-volt operation making it ideally suited for dual supply range systems or card products that are pluggable in both 3-volt and 5-volt hosts.

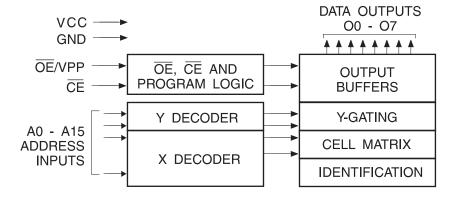
Atmel's AT27BV512 has additional features to ensure high quality and efficient production use. The Rapid™ Program-

ming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100 $\mu s/byte$. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages. The AT27BV512 programs exactly the same way as a standard 5V AT27C512R and uses the same programming equipment.

System Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed data sheet limits, resulting in device non-conformance. At a minimum, a 0.1 μF high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7 μF bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

Block Diagram



Absolute Maximum Ratings*

| Temperature Under Bias40°C to +85°C |
|--|
| Storage Temperature65°C to +125°C |
| Voltage on Any Pin with Respect to Ground2.0V to +7.0V ⁽¹⁾ |
| Voltage on A9 with Respect to Ground2.0V to +14.0V ⁽¹⁾ |
| V _{PP} Supply Voltage with Respect to Ground2.0V to +14.0V ⁽¹⁾ |

*NOTICE: Stresses beyond those listed under "Absolute

Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect

device reliability

Note:

Minimum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is V_{CC} + 0.75V dc which may be exceeded if certain precautions are observed (consult application notes) and which may overshoot to +7.0V for pulses of less than 20 ns.

Operating Modes

| Mode \ Pin | CE | OE/V _{PP} | Ai | V _{cc} | Outputs |
|--|-----------------|--------------------|---|--------------------------------|---------------------|
| Read ⁽²⁾ | V _{IL} | V _{IL} | Ai | V _{CC} ⁽²⁾ | D _{OUT} |
| Output Disable ⁽²⁾ | V _{IL} | V _{IH} | X ⁽¹⁾ | V _{CC} ⁽²⁾ | High Z |
| Standby ⁽²⁾ | V _{IH} | X | X | $V_{CC}^{(2)}$ | High Z |
| Rapid Program ⁽³⁾ | V _{IL} | V _{PP} | Ai | V _{CC} ⁽³⁾ | D _{IN} |
| PGM Verify ⁽³⁾ | V _{IL} | V _{IL} | Ai | V _{CC} ⁽³⁾ | D _{OUT} |
| PGM Inhibit ⁽³⁾ | V _{IH} | V _{PP} | X | V _{CC} ⁽³⁾ | High Z |
| Product Identification ⁽³⁾⁽⁵⁾ | V _{IL} | V _{IL} | $A9 = V_H^{(4)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A15 = V_{IL}$ | V _{CC} ⁽³⁾ | Identification Code |

- Notes: 1. X can be V_{IL} or V_{IH} .
 - 2. Read, output disable, and standby modes require, 2.7V \leq V_{CC} \leq 3.6V, or 4.5V \leq V_{CC} \leq 5.5V.
 - 3. Refer to Programming Characteristics. Programming modes require V_{CC} = 6.5V.
 - 4. $V_H = 12.0 \pm 0.5 V$.
 - 5. Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}), except A9 which is set to V_H and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code byte.





DC and AC Operating Conditions for Read Operation

| | | AT27BV512 | | | | | | |
|------------------------------|------|--------------|--------------|--------------|--------------|--|--|--|
| | | -70 | -90 | -12 | -15 | | | |
| Operating Temperature (Case) | Com. | 0°C - 70°C | 0°C - 70°C | 0°C - 70°C | 0°C - 70°C | | | |
| | Ind. | -40°C - 85°C | -40°C - 85°C | -40°C - 85°C | -40°C - 85°C | | | |
| V 5 0 1 | | 2.7V to 3.6V | 2.7V to 3.6V | 2.7V to 3.6V | 2.7V to 3.6V | | | |
| V _{CC} Power Supply | | 5V ± 10% | 5V ± 10% | 5V ± 10% | 5V ± 10% | | | |

DC and Operating Characteristics for Read Operation

| Symbol | Parameter | Condition | Min | Max | Units |
|---------------------------------|---|--|-----------------------|-----------------------|-------|
| V _{CC} = 2.7V | to 3.6V | | | | |
| I _{LI} | Input Load Current | V _{IN} = 0V to V _{CC} | | ±1 | μΑ |
| I _{LO} | Output Leakage Current | V _{OUT} = 0V to V _{CC} | | ±5 | μΑ |
| I _{PP1} ⁽²⁾ | V _{PP} ⁽¹⁾ Read/Standby Current | $V_{PP} = V_{CC}$ | | 10 | μΑ |
| | V (1) Charadha Carrant | I_{SB1} (CMOS), $\overline{CE} = V_{CC \pm} 0.3V$ | | 20 | μΑ |
| I _{SB} | V _{CC} ⁽¹⁾ Standby Current | I_{SB2} (TTL), \overline{CE} = 2.0 to V_{CC} + 0.5V | | 100 | μΑ |
| I _{CC} | V _{CC} Active Current | $f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE} = V_{IL}, V_{CC} = 3.6V$ | | 8 | mA |
| ., | Leavest Leave Vallages | V _{CC} = 3.0 to 3.6V | -0.6 | 0.8 | V |
| V_{IL} | Input Low Voltage | V _{CC} = 2.7 to 3.6V | -0.6 | 0.2 x V _{CC} | V |
| ., | | V _{CC} = 3.0 to 3.6V | 2.0 | V _{CC} + 0.5 | V |
| V_{IH} | Input High Voltage | V _{CC} = 2.7 to 3.6V | 0.7 x V _{CC} | V _{CC} + 0.5 | V |
| | | I _{OL} = 2.0 mA | | 0.4 | V |
| V_{OL} | Output Low Voltage | I _{OL} = 100 μA | | 0.2 | V |
| | | I _{OL} = 20 μA | | 0.1 | V |
| | | I _{OH} = -2.0 mA | 2.4 | | V |
| V_{OH} | Output High Voltage | I _{OH} = -100 μA | V _{CC} - 0.2 | | V |
| | | I _{OH} = -20 μA | V _{CC} - 0.1 | | V |
| V _{CC} = 4.5V | to 5.5V | | | | |
| ILI | Input Load Current | V _{IN} = 0V to V _{CC} | | ±1 | μΑ |
| I _{LO} | Output Leakage Current | V _{OUT} = 0V to V _{CC} | | ±5 | μΑ |
| I _{PP1} ⁽²⁾ | V _{PP} ⁽¹⁾ Read/Standby Current | $V_{PP} = V_{CC}$ | | 10 | μΑ |
| | V (1) Chandley Company | I_{SB1} (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$ | | 100 | μΑ |
| I _{SB} | V _{CC} ⁽¹⁾ Standby Current | I_{SB2} (TTL), \overline{CE} = 2.0 to V_{CC} + 0.5V | | 1 | mA |
| I _{CC} | V _{CC} Active Current | $f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE} = V_{IL}$ | | 20 | mA |
| V _{IL} | Input Low Voltage | | -0.6 | 0.8 | V |
| V _{IH} | Input High Voltage | | 2.0 | V _{CC} + 0.5 | V |
| V _{OL} | Output Low Voltage | I _{OL} = 2.1 mA | | 0.4 | V |
| V _{OH} | Output High Voltage | I _{OH} = -400 μA | 2.4 | | V |

Notes: 1. V_{CC} must be applied simultaneously with or before \overline{OE}/V_{PP} and removed simultaneously with or after \overline{OE}/V_{PP}

AT27BV512

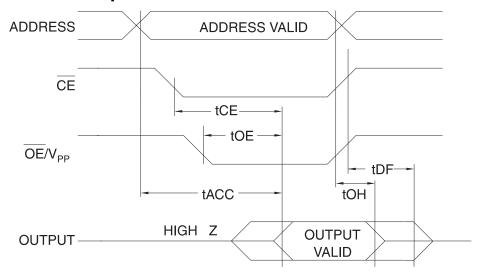
^{2.} V_{PP} may be connected directly to V_{CC} , except during programming. The supply current would then be the sum of I_{CC} and I_{PP}

AC Characteristics for Read Operation

 $V_{CC} = 2.7V$ to 3.6V and 4.5V to 5.5V

| | | | | AT27BV512 | | | | | | | |
|-----------------------------------|---|---|-----|-----------|-----|-----|-----|-----|-----|-----|-------|
| | | | -7 | 70 | -90 | | -1: | | -15 | | |
| Symbol | Parameter | Condition | Min | Max | Min | Max | Min | Max | Min | Max | Units |
| t _{ACC} (3) | Address to Output Delay | $\overline{CE} = \overline{OE}/V_{PP} = V_{IL}$ | | 70 | | 90 | | 120 | | 150 | ns |
| t _{CE} ⁽²⁾ | CE to Output Delay | $\overline{OE/V_{PP}} = V_{IL}$ | | 70 | | 90 | | 120 | | 150 | ns |
| t _{OE} ⁽²⁾⁽³⁾ | OE/V _{PP} to Output Delay | CE = V _{IL} | | 50 | | 50 | | 50 | | 60 | ns |
| t _{DF} ⁽⁴⁾⁽⁵⁾ | OE/V _{PP} or CE High to Output Float, whichever occurred first | | | 40 | | 40 | | 40 | | 50 | ns |
| t _{OH} | Output Hold from Address, CE or OE/V _{PP} whichever occurred first | | 0 | | 0 | | 0 | | 0 | | ns |

AC Waveforms for Read Operation(1)



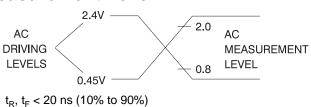
Notes:

- 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.
- 2. $\overline{\text{OE}}/\text{V}_{PP}$ may be delayed up to t_{CE} - t_{OE} after the falling edge of $\overline{\text{CE}}$ without impact on t_{CE} .
- 3. $\overline{\text{OE}}/V_{PP}$ may be delayed up to t_{ACC} - t_{OE} after the address is valid without impact on t_{ACC} .
- 4. This parameter is only sampled and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.
- 6. When reading a 27BV256, a 0.1 μF capacitor is required across V_{CC} and ground to suppress spurious voltage transients.

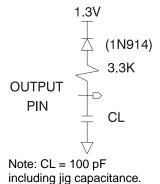




Input Test Waveform and Measurement Level



Output Test Load



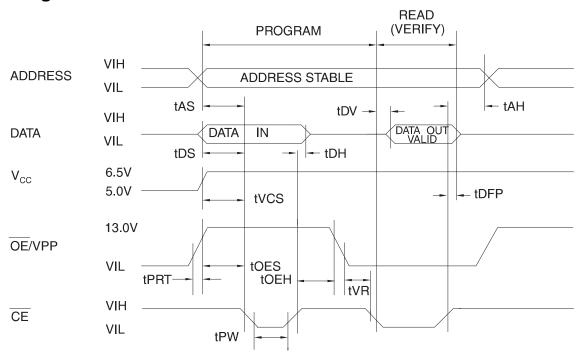
Pin Capacitance

 $f = 1 \text{ MHz}, T = 25^{\circ}C^{(1)}$

| Symbol | Тур | Max | Units | Conditions | |
|------------------|-----|-----|-------|-----------------------|--|
| C _{IN} | 4 | 6 | pF | $V_{IN} = 0V$ | |
| C _{OUT} | 8 | 12 | pF | V _{OUT} = 0V | |

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

Programming Waveforms⁽¹⁾



Notes:

- 1. The Input Timing Reference is 0.8V for $V_{\rm IL}$ and 2.0V for $V_{\rm IH}$.
- 2. t_{OE} and t_{DFP} are characteristics of the device but must be accommodated by the programmer.
- 3. When programming the AT27BV512, a 0.1 μ F capacitor is required across V_{PP} and ground to suppress spurious voltage transients.

DC Programming Characteristics

 T_A = 25 \pm 5°C, V_{CC} = 6.5 \pm 0.25V, \overline{OE}/V_{PP} = 13.0 \pm 0.25V

| | | | Limits | | |
|------------------|---|---------------------------|--------|-----------------------|-------|
| Symbol | Parameter | Test Conditions | Min | Max | Units |
| I _{LI} | Input Load Current | $V_{IN} = V_{IL}, V_{IH}$ | | ±10 | μΑ |
| V_{IL} | Input Low Level | | -0.6 | 0.8 | V |
| V_{IH} | Input High Level | | 2.0 | V _{CC} + 0.5 | ٧ |
| V _{OL} | Output Low Voltage | I _{OL} = 2.1 mA | | 0.4 | V |
| V _{OH} | Output High Voltage | I _{OH} = -400 μA | 2.4 | | V |
| I _{CC2} | V _{CC} Supply Current (Program and Verify) | | | 25 | mA |
| I _{PP2} | ŌE/V _{PP} Current | CE = V _{IL} | | 25 | mA |
| V _{ID} | A9 Product Identification Voltage | | 11.5 | 12.5 | V |





AC Programming Characteristics

 $T_A = 25 \pm 5^{\circ}C$, $V_{CC} = 6.5 \pm 0.25V$, $\overline{OE}/V_{PP} = 13.0 \pm 0.25V$

| | | | Lir | nits | |
|------------------|--|---|-----|------|-------|
| Symbol | Parameter | Test Conditions ⁽¹⁾ | Min | Max | Units |
| t _{AS} | Address Setup Time | | 2 | | μs |
| t _{OES} | ŌĒ/V _{PP} Setup Time | | 2 | | μs |
| t _{OEH} | OE/V _{PP} Hold Time | Input Rise and Fall Times: | 2 | | μs |
| t _{DS} | Data Setup Time | (10% to 90) 20 ns | 2 | | μs |
| t _{AH} | Address Hold Time | Input Pulse Levels: | 0 | | μs |
| t _{DH} | Data Hold Time | 0.45V to 2.4V | 2 | | μs |
| t _{DFP} | CE High to Output Float Delay ⁽²⁾ | | 0 | 130 | ns |
| t _{VCS} | V _{CC} Setup Time | Input Timing Reference Level: 0.8V to 2.0V | 2 | | μs |
| t _{PW} | CE Program Pulse Width ⁽³⁾ | 0.01 10 2.01 | 95 | 105 | μs |
| t _{DV} | Data Valid from $\overline{CE}^{(2)}$ | Output Timing Reference Level: | | 1 | μs |
| t _{VR} | ŌĒ/V _{PP} Recovery Time | 0.8V to 2.0V | 2 | | μs |
| t _{PRT} | OE/V _{PP} Pulse Rise Time During Programming | | 50 | | ns |

Notes: 1. V_{CC} must be applied simultaneously or before \overline{OE}/V_{PP} and removed simultaneously or after \overline{OE}/V_{PP}

- 2. This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven—see timing diagram.
- 3. Program Pulse width tolerance is 100 $\mu\text{sec}\pm5\%.$

Atmel's 27BV512 Integrated Product Identification Code⁽¹⁾

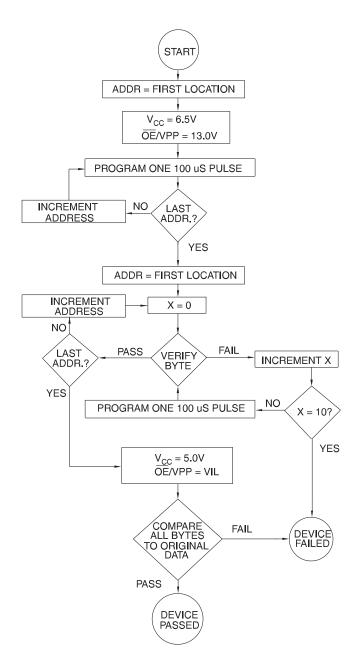
| | | Pins | | | | | | Hex | | |
|--------------|----|------|----|----|----|----|----|-----|----|------|
| Codes | A0 | 07 | O6 | O5 | 04 | О3 | 02 | 01 | 00 | Data |
| Manufacturer | 0 | 0 | 0 | 0 | 1 | 1 | 1 | 1 | 0 | 1E |
| Device Type | 1 | 0 | 0 | 0 | 0 | 1 | 1 | 0 | 1 | 0D |

Note: 1. The AT27BV512 has the same Product Identification Code as the AT27C512R. Both are programming compatible.

Rapid Programming Algorithm

A 100 μs \overline{CE} pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and \overline{OE}/V_{PP} is raised to 13.0V. Each address is first programmed with one 100 μs \overline{CE} pulse without verification. Then a verification / reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100 μs pulses are applied with a verification after each

pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. $\overline{\text{OE}}/\text{V}_{\text{PP}}$ is then lowered to V $_{\text{IL}}$ and V $_{\text{CC}}$ to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.







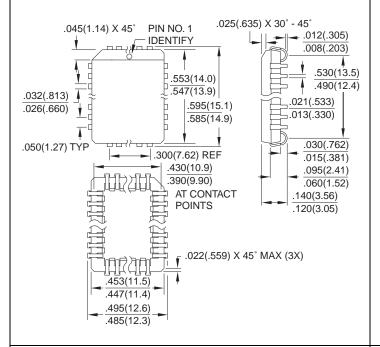
Ordering Information

| t _{ACC} | I _{CC} (mA) | | | | |
|------------------|----------------------|---------|----------------|---------|-----------------|
| (ns) | Active | Standby | Ordering Code | Package | Operation Range |
| 70 | 8 | 0.02 | AT27BV512-70JC | 32J | Commercial |
| | | | AT27BV512-70RC | 28R | (0°C to 70°C) |
| | | | AT27BV512-70TC | 28T | |
| | 8 | 0.02 | AT27BV512-70JI | 32J | Industrial |
| | | | AT27BV512-70RI | 28R | (-40°C to 85°C) |
| | | | AT27BV512-70TI | 28T | |
| 90 | 8 | 0.02 | AT27BV512-90JC | 32J | Commercial |
| | | | AT27BV512-90RC | 28R | (0°C to 70°C) |
| | | | AT27BV512-90TC | 28T | |
| | 8 | 0.02 | AT27BV512-90JI | 32J | Industrial |
| | | | AT27BV512-90RI | 28R | (-40°C to 85°C) |
| | | | AT27BV512-90TI | 28T | |
| 120 | 8 | 0.02 | AT27BV512-12JC | 32J | Commercial |
| | | | AT27BV512-12RC | 28R | (0°C to 70°C) |
| | | | AT27BV512-12TC | 28T | |
| | 8 | 0.02 | AT27BV512-12JI | 32J | Industrial |
| | | | AT27BV512-12RI | 28R | (-40°C to 85°C) |
| | | | AT27BV512-12TI | 28T | |
| 150 | 8 | 0.02 | AT27BV512-15JC | 32J | Commercial |
| | | | AT27BV512-15RC | 28R | (0°C to 70°C) |
| | | | AT27BV512-15TC | 28T | |
| | 8 | 0.02 | AT27BV512-15JI | 32J | Industrial |
| | | | AT27BV512-15RI | 28R | (-40°C to 85°C) |
| | | | AT27BV512-15TI | 28T | |

| | Package Type | | | | |
|-----|--|--|--|--|--|
| 32J | 32-Lead, Plastic J-Leaded Chip Carrier (PLCC) | | | | |
| 28R | 28-Lead, 0.330" Wide, Plastic Gull Wing Small Package (SOIC) | | | | |
| 28T | 28-Lead, Plastic Thin Small Outline Package (TSOP) | | | | |

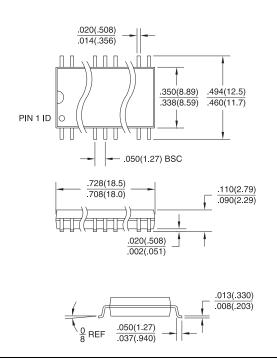
Packaging Information

32J, 32-Lead, Plastic J-Leaded Chip Carrier (PLCC) Dimensions in Inches and (Millimeters)
JEDEC STANDARD MS-016 AE



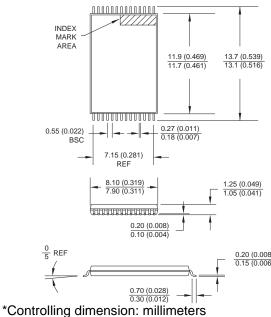
28R, 28-Lead, 0.330" Wide, Plastic Gull Wing Small Outline (SOIC)

Dimensions in Inches and (Millimeters)



28T, 28-Lead, Plastic Thin Small Outline Package (TSOP)

Dimensions in Millimeters and (Inches)*









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